


<b>Search Notes</b>  	<b>Application/Control No.</b>  10591152	<b>Applicant(s)/Patent Under Reexamination</b>  NAKAHARA ET AL.
	<b>Examiner</b>  LEON-VIET Q NGUYEN	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
327	140, 159	8/19/09	LVN
375	355	8/19/09	LVN

SEARCH NOTES		
Search Notes	Date	Examiner
inventor name search for double patenting in EAST	8/19/09	LVN
EAST search history	8/17/09-8/19/09	LVN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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